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	FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office LIST OF DOCUMENTS CITED BY APPLICANT					Attorney Docket Number 9180-29		
LIST	OF DO	OCUMENTS CITE	D BY APPLI	CANT				Assigned
	(U	lse several sheets if	necessary)					L
					Applicants:	Krishna K. N	lair et al;	
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			U. S	. PATENT DO	CUMENTS			
Examiner Initial		Document Number	Date	N	ame	Class	Subclass	Filing Date if Appropriate
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DM	2.	K. Zeng et al; Six Reports: A Revie	K. Zeng et al; Six cases of reliability study of Pb-free solder joints in electronic packaging technology, Reports: A Review Journal; Materials Science and Engineering R 38 (2002) pp 55-105.					
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DATE CONSIDERED 16/07
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Substitute form 1449A/PTS	PE VCZ	С	omplete if Known
1		Application Number	10/601,938
INFORMATION DISCLOSURI	a sook is	Filing Date	June 23, 2003
STATEMENT BY APPLICANT	WE 0 6 5004 2	First Named Inventor	Krishna K. Nair
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			U.S. PATENTS	AND PATENT PUBLICATIONS		
Examiner Initials*	Cite No.	U.S. Patent	Document	Name of Patentee or Applicant of Cited	Date of Publication of Cited	
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Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published					
							
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not in conformance and	not considered.	Include copy of this fo	rm with next communication	ation to applicant.	

Substitute form 1449	APTO	OIPE	c	omplete if Known	
	/	3	Application Number	10/601,938	
INFORMATION	DISCLOSURE	1114 1 4 2004 E	Filing Date	June 23, 2003	
STATEMENT BY	APPLICAN TO	TINH 1 4 Sep.	First Named Inventor	Krishna K. Nair	
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